## INTEGRATED CIRCUITS

## DATA SHEET

# **74LVC2G07**Buffers with open-drain outputs

Product specification Supersedes data of 2004 Mar 19 2004 Sep 08





## **Buffers with open-drain outputs**

74LVC2G07

#### **FEATURES**

- Wide supply voltage range from 1.65 V to 5.5 V
- 5 V tolerant input/output for interfacing with 5 V logic
- · High noise immunity
- Complies with JEDEC standard:
  - JESD8-7 (1.65 V to 1.95 V)
  - JESD8-5 (2.3 V to 2.7 V)
  - JESD8B/JESD36 (2.7 V to 3.6 V).
- –24 mA output drive (V<sub>CC</sub> = 3.0 V)
- CMOS low power consumption
- Latch-up performance exceeds 250 mA
- · Direct interface with TTL levels
- Inputs accept voltages up to 5 V
- · Multiple package options
- ESD protection:
  - HBM EIA/JESD22-A114-B exceeds 2000 V
  - MM EIA/JESD22-A115-A exceeds 200 V.
- Specified from -40 °C to +85 °C and -40 °C to +125 °C.

#### DESCRIPTION

The 74LVC2G07 is a high-performance, low-power, low-voltage, Si-gate CMOS device superior to most advanced CMOS compatible TTL families.

Input can be driven from either 3.3 V or 5 V devices. This feature allows the use of this device in a mixed 3.3 V and 5 V environment.

Schmitt trigger action at all inputs makes the circuit tolerant for slower input rise and fall time.

This device is fully specified for partial power-down applications using  $I_{\text{off}}$ . The  $I_{\text{off}}$  circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

The 74LVC2G07 provides two non-inverting buffers.

The output of the device is an open drain and can be connected to other open-drain outputs to implement active-LOW wired-OR or active-HIGH wired-AND functions.

#### **QUICK REFERENCE DATA**

GND = 0 V;  $T_{amb}$  = 25 °C.

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t <sub>PLZ</sub> /t <sub>PZL</sub>	propagation delay input nA to output nY	$V_{CC} = 1.8 \text{ V}; C_L = 30 \text{ pF}; R_L = 1 \text{ k}\Omega$	3.5	ns
		$V_{CC} = 2.5 \text{ V}; C_L = 30 \text{ pF}; R_L = 500 \Omega$	2.4	ns
		$V_{CC} = 2.7 \text{ V}; C_L = 50 \text{ pF}; R_L = 500 \Omega$	2.3	ns
		$V_{CC} = 3.3 \text{ V}; C_L = 50 \text{ pF}; R_L = 500 \Omega$	2.6	ns
		$V_{CC} = 5.0 \text{ V}; C_L = 50 \text{ pF}; R_L = 500 \Omega$	1.5	ns
Cı	input capacitance		2.5	pF
C <sub>PD</sub>	power dissipation capacitance per gate	V <sub>CC</sub> = 3.3 V; notes 1 and 2	6.5	pF

#### Notes

1.  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \sum (C_L \times V_{CC}^2 \times f_o)$  where:

 $f_i$  = input frequency in MHz;

f<sub>o</sub> = output frequency in MHz;

C<sub>L</sub> = output load capacitance in pF;

V<sub>CC</sub> = supply voltage in Volts;

N = total load switching outputs;

 $\sum (C_L \times V_{CC}^2 \times f_o) = \text{sum of outputs.}$ 

2. The condition is  $V_I = GND$  to  $V_{CC}$ .

Product specification Philips Semiconductors

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#### **FUNCTION TABLE**

See note 1.

INPUT	ОИТРИТ
nA	nY
L	L
Н	Z

#### Note

1. H = HIGH voltage level;

L = LOW voltage level;

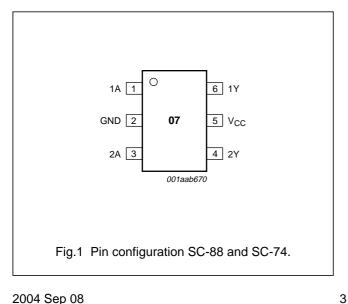
Z = high-impedance OFF-state.

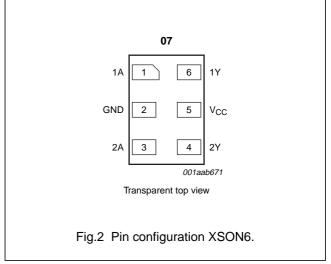
#### **ORDERING INFORMATION**

TYPE NUMBER			PACKAGE			
I TPE NOMBER	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE	MARKING
74LVC2G07GW	-40 °C to +125 °C	6	SC-88	plastic	SOT363	V7
74LVC2G07GV	–40 °C to +125 °C	6	SC-74	plastic	SOT457	V07
74LVC2G07GM	-40 °C to +125 °C	6	XSON6	plastic	SOT886	V7

#### **PINNING**

PIN	SYMBOL	DESCRIPTION
1	1A	data input
2	GND	ground (0 V)
3	2A	data input
4	2Y	data output
5	V <sub>CC</sub>	supply voltage
6	1Y	data output

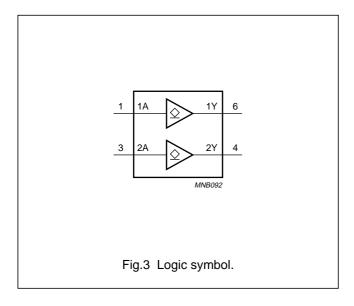


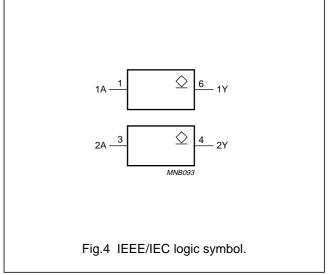


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#### RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage		1.65	5.5	V
VI	input voltage		0	5.5	V
Vo	output voltage	active mode	0	V <sub>CC</sub>	V
		V <sub>CC</sub> = 0 V; Power-down mode	0	5.5	V
T <sub>amb</sub>	operating ambient temperature		-40	+125	°C
t <sub>r</sub> , t <sub>f</sub>	input rise and fall times	V <sub>CC</sub> = 1.65 V to 2.7 V	0	20	ns/V
		V <sub>CC</sub> = 2.7 V to 5.5 V	0	10	ns/V

#### **LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage		-0.5	+6.5	V
I <sub>IK</sub>	input diode current	V <sub>I</sub> < 0 V	_	-50	mA
VI	input voltage	note 1	-0.5	+6.5	V
I <sub>OK</sub>	output diode current	V <sub>O</sub> < 0 V	_	-50	mA
Vo	output voltage	active mode; notes 1 and 2	-0.5	+6.5	V
		Power-down mode; notes 1 and 2	-0.5	+6.5	V
Io	output source or sink current	V <sub>O</sub> = 0 V to 6.5 V	_	50	mA
I <sub>CC</sub> , I <sub>GND</sub>	V <sub>CC</sub> or GND current		_	±100	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	power dissipation	$T_{amb} = -40  ^{\circ}\text{C} \text{ to } +125  ^{\circ}\text{C}$	_	300	mW

#### **Notes**

- 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 2. When  $V_{CC}$  = 0 V (Power-down mode), the output voltage can be 5.5 V in normal operation.

## Buffers with open-drain outputs

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#### **DC CHARACTERISTICS**

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CVMDOL		TEST COND	ITIONS	NAIN!	TVD	BAAV	LINUT
SYMBOL	PARAMETER	OTHER	V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	UNIT
T <sub>amb</sub> = -40	) °C to +85 °C; note 1				•		•
V <sub>IH</sub>	HIGH-level input voltage		1.65 to 1.95	$0.65 \times V_{CC}$	_	_	V
			2.3 to 2.7	1.7	_	_	V
			2.7 to 3.6	2.0	_	_	V
			4.5 to 5.5	$0.7 \times V_{CC}$	_	_	V
V <sub>IL</sub>	LOW-level input voltage		1.65 to 1.95	_	_	$0.35 \times V_{CC}$	V
			2.3 to 2.7	_	_	0.7	V
			2.7 to 3.6	_	_	0.8	V
			4.5 to 5.5	_	_	$0.3 \times V_{CC}$	V
V <sub>OL</sub>	LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$					
		I <sub>O</sub> = 100 μA	1.65 to 5.5	_	_	0.1	V
		I <sub>O</sub> = 4 mA	1.65	_	_	0.45	V
		I <sub>O</sub> = 8 mA	2.3	_	_	0.3	V
		I <sub>O</sub> = 12 mA	2.7	_	_	0.4	V
		I <sub>O</sub> = 24 mA	3.0	_	_	0.55	V
		I <sub>O</sub> = 32 mA	4.5	_	_	0.55	V
ILI	input leakage current	V <sub>I</sub> = 5.5 V or GND	1.65 to 5.5	_	±0.1	±5	μΑ
I <sub>OZ</sub>	output OFF-state current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	5.5	_	±0.1	±10	μΑ
I <sub>off</sub>	power OFF leakage current	$V_I$ or $V_O = 5.5 \text{ V}$	0	_	±0.1	±10	μΑ
Icc	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A	5.5	_	0.1	10	μΑ
Δl <sub>CC</sub>	additional quiescent supply current per pin	$V_I = V_{CC} - 0.6 \text{ V};$ $I_O = 0 \text{ A}$	2.3 to 5.5	_	5	500	μΑ

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OVMBOL	DADAMETER	TEST COND	ITIONS		TVD	BAAV	
SYMBOL	PARAMETER	OTHER	V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	UNIT
T <sub>amb</sub> = -40	) °C to +125 °C		•	,			•
V <sub>IH</sub>	HIGH-level input voltage		1.65 to 1.95	$0.65 \times V_{CC}$	_	_	V
			2.3 to 2.7	1.7	_	_	V
			2.7 to 3.6	2.0	_	_	V
			4.5 to 5.5	$0.7 \times V_{CC}$	_	_	V
V <sub>IL</sub>	LOW-level input voltage		1.65 to 1.95	_	_	$0.35 \times V_{CC}$	V
			2.3 to 2.7	_	_	0.7	V
			2.7 to 3.6	_	_	0.8	V
			4.5 to 5.5	_	_	$0.3 \times V_{CC}$	V
V <sub>OL</sub>	LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$					
		I <sub>O</sub> = 100 μA	1.65 to 5.5	_	_	0.1	V
		I <sub>O</sub> = 4 mA	1.65	_	_	0.70	V
		I <sub>O</sub> = 8 mA	2.3	_	_	0.45	V
		I <sub>O</sub> = 12 mA	2.7	_	_	0.60	V
		I <sub>O</sub> = 24 mA	3.0	_	_	0.80	V
		I <sub>O</sub> = 32 mA	4.5	_	_	0.80	V
ILI	input leakage current	V <sub>I</sub> = 5.5 V or GND	1.65 to 5.5	_	_	±20	μΑ
I <sub>OZ</sub>	output OFF-state current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = V_{CC} \text{ or GND}$	5.5	_	_	±10	μΑ
I <sub>off</sub>	power OFF leakage current	$V_I$ or $V_O = 5.5 \text{ V}$	0	_	_	±20	μΑ
I <sub>CC</sub>	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A	5.5	-	-	40	μΑ
$\Delta I_{CC}$	additional quiescent supply current per pin	$V_{I} = V_{CC} - 0.6 \text{ V};$ $I_{O} = 0 \text{ A}$	2.3 to 5.5	_	_	5000	μΑ

#### Note

<sup>1.</sup> All typical values are measured at  $V_{CC}$  = 3.3 V and  $T_{amb}$  = 25  $^{\circ}C.$ 

## Buffers with open-drain outputs

74LVC2G07

#### **AC CHARACTERISTICS**

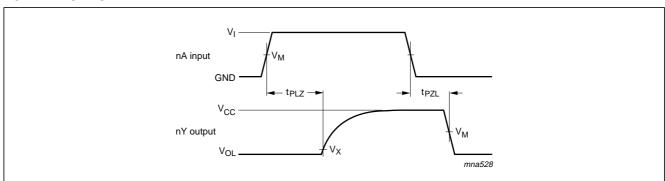
GND = 0 V.

CVMDOL	DADAMETED	TEST CON	DITIONS	MINI	TVD	MAY	LINUT
SYMBOL	PARAMETER	WAVEFORMS	V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	UNIT
T <sub>amb</sub> = -40	) °C to +85 °C; note 1	•	•	•			
t <sub>PLZ</sub> /t <sub>PZL</sub>	propagation delay input nA to	see Figs 5 and 6	1.65 to 1.95	1.0	3.5	6.7	ns
	output nY		2.3 to 2.7	0.5	2.4	4.3	ns
			2.7	1.0	2.3	4.2	ns
			3.0 to 3.6	0.5	2.6	3.7	ns
			4.5 to 5.5	0.5	1.5	2.9	ns
T <sub>amb</sub> = -40	) °C to +125 °C	,					
t <sub>PLZ</sub> /t <sub>PZL</sub>	propagation delay input nA to	see Figs 5 and 6	1.65 to 1.95	1.0	3.5	8.4	ns
	output nY		2.3 to 2.7	0.5	2.4	5.5	ns
			2.7	1.0	2.3	5.3	ns
			3.0 to 3.6	0.5	2.6	4.7	ns
			4.5 to 5.5	0.5	1.5	3.7	ns

#### Note

1. All typical values are measured at  $T_{amb}$  = 25 °C and at  $V_{CC}$  = 1.8 V, 2.5 V, 2.7 V, 3.3 V and 5.0 V respectively.

#### **AC WAVEFORMS**



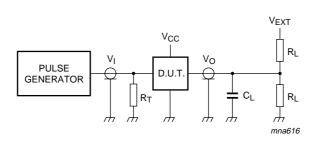
V <sub>CC</sub>	V <sub>M</sub>	V <sub>X</sub>	INF	PUT
▼CC	V M	VX	VI	$t_r = t_f$
1.65 V to 1.95 V	$0.5 \times V_{CC}$	V <sub>OL</sub> + 0.15 V	V <sub>CC</sub>	≤ 2.0 ns
2.3 V to 2.7 V	$0.5 \times V_{CC}$	V <sub>OL</sub> + 0.15 V	V <sub>CC</sub>	≤ 2.0 ns
2.7 V	1.5 V	V <sub>OL</sub> + 0.3 V	2.7 V	≤ 2.5 ns
3.0 V to 3.6 V	1.5 V	V <sub>OL</sub> + 0.3 V	2.7 V	≤ 2.5 ns
4.5 V to 5.5 V	$0.5 \times V_{CC}$	V <sub>OL</sub> + 0.3 V	V <sub>CC</sub>	≤ 2.5 ns

 $\ensuremath{V_{\text{OL}}}$  and  $\ensuremath{V_{\text{OH}}}$  are typical output voltage drop that occur with the output load.

Fig.5 Input nA to output nY propagation delays.

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V <sub>-</sub> -	V <sub>I</sub>	CL	$R_L$	V <sub>EXT</sub>
V <sub>CC</sub>	"	O <sub>L</sub>	I KL	t <sub>PZL</sub> /t <sub>PLZ</sub>
1.65 V to 1.95 V	V <sub>CC</sub>	30 pF	1 kΩ	$2 \times V_{CC}$
2.3 V to 2.7 V	V <sub>CC</sub>	30 pF	500 Ω	$2 \times V_{CC}$
2.7 V	2.7 V	50 pF	500 Ω	6 V
3.0 V to 3.6 V	2.7 V	50 pF	500 Ω	6 V
4.5 V to 5.5 V	V <sub>CC</sub>	50 pF	500 Ω	$2 \times V_{CC}$

Definitions for test circuit:

R<sub>L</sub> = Load resistor.

 $\ensuremath{C_L}$  = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to the output impedance  $Z_0$  of the pulse generator.

Fig.6 Load circuitry for switching times.

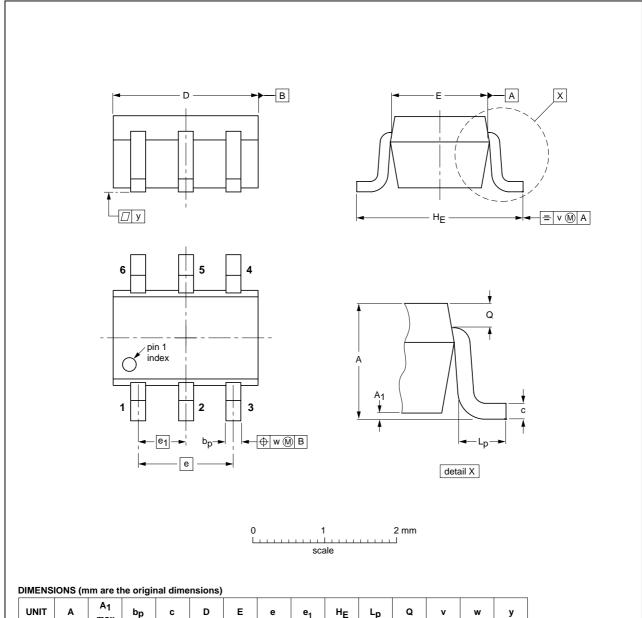
## Buffers with open-drain outputs

74LVC2G07

#### **PACKAGE OUTLINES**

#### Plastic surface mounted package; 6 leads

**SOT363** 



UNIT	Α	max	bp	С	D	Е	е	e <sub>1</sub>	HE	Lp	Q	V	w	у
mm	1.1 0.8	0.1	0.30 0.20	0.25 0.10	2.2 1.8	1.35 1.15	1.3	0.65	2.2 2.0	0.45 0.15	0.25 0.15	0.2	0.2	0.1

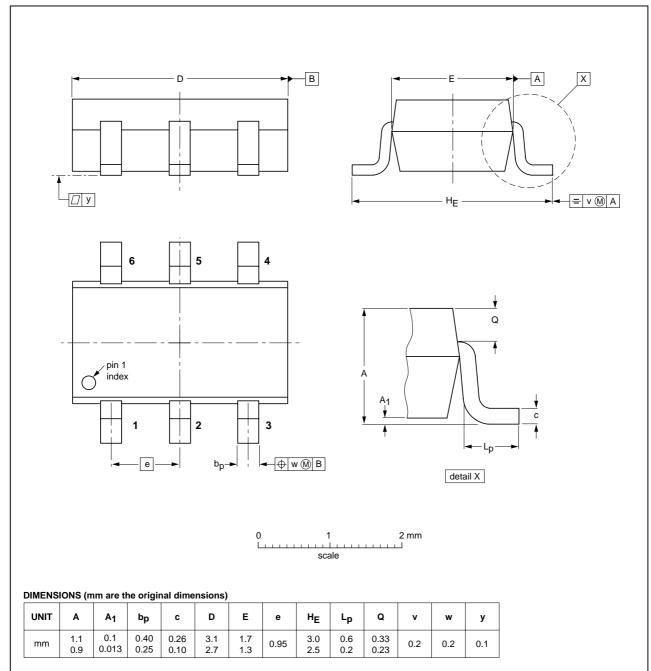
OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT363			SC-88			97-02-28

## Buffers with open-drain outputs

## 74LVC2G07

#### Plastic surface mounted package; 6 leads

SOT457



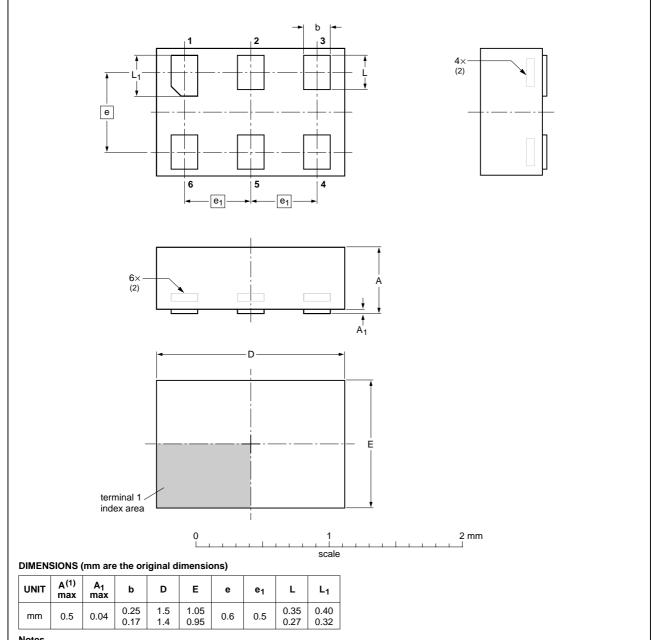
OUTLINE VERSION	REFERENCES			EUROPEAN	ISSUE DATE	
	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT457			SC-74			<del>97-02-28</del> 01-05-04

## Buffers with open-drain outputs

## 74LVC2G07

XSON6: plastic extremely thin small outline package; no leads; 6 terminals; body 1 x 1.45 x 0.5 mm

**SOT886** 



#### Notes

- 1. Including plating thickness.
- 2. Can be visible in some manufacturing processes.

OUTLINE	REFERENCES				EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT886		MO-252				<del>-04-07-15</del> 04-07-22

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#### **DATA SHEET STATUS**

LEVEL	DATA SHEET STATUS <sup>(1)</sup>	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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- 3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

#### **DEFINITIONS**

**Short-form specification** — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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